

September 2009

MCT5201M, MCT5210M, MCT5211M Low Input Current Phototransistor Optocouplers

Features

- High CTR_{CE(SAT)} comparable to Darlingtons
- CTR guaranteed 0°C to 70°C
- High common mode transient rejection 5kV/µs
- Data rates up to 150kbits/s (NRZ)
- Underwriters Laboratory (UL) recognized, file #E90700, volume 2
- IEC60747-5-2 approved (ordering option V)

Applications

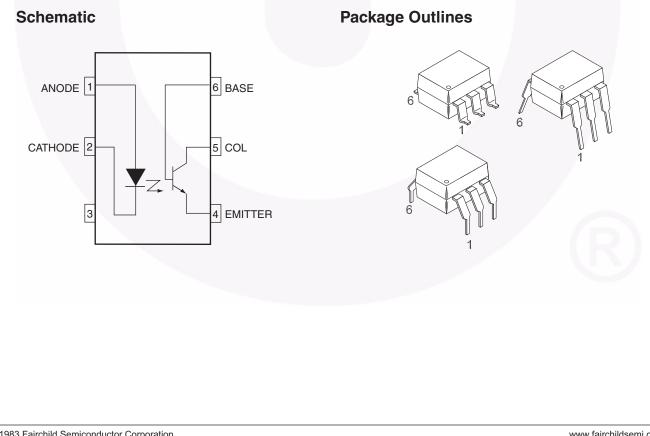
- CMOS to CMOS/LSTTL logic isolation
- LSTTL to CMOS/LSTTL logic isolation
- RS-232 line receiver
- Telephone ring detector
- AC line voltage sensing
- Switching power supply

Description

The MCT52XXM series consists of a high-efficiency AlGaAs, infrared emitting diode, coupled with an NPN phototransistor in a six pin dual-in-line package.

The MCT52XXM is well suited for CMOS to LSTT/TTL interfaces, offering 250% CTR_{CE(SAT)} with 1mA of LED input current. When an LED input current of 1.6mA is supplied data rates to 20K bits/s are possible.

The MCT52XXM can easily interface LSTTL to LSTTL/ TTL, and with use of an external base to emitter resistor data rates of 100K bits/s can be achieved.



Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameters	Value	Units				
TOTAL DEVICE							
T _{STG}	Storage Temperature	-55 to +150	°C				
T _{OPR}	Operating Temperature	-40 to +100	°C				
T _{SOL}	Lead Solder Temperature	260 for 10 sec	°C				
PD	Total Device Power Dissipation @ 25°C (LED plus detector)	260	mW				
	Derate Linearly From 25°C	3.5	mW/°C				
EMITTER							
١ _F	Continuous Forward Current	50	mA				
V _R	Reverse Input Voltage	6	V				
l _F (pk)	Forward Current - Peak (1 µs pulse, 300 pps)	3.0	A				
PD	LED Power Dissipation	75	mW				
	Derate Linearly From 25°C	1.0	mW/°C				
DETECTO	R						
Ι _C	Continuous Collector Current	150	mA				
PD	Detector Power Dissipation	150	mW				
	Derate Linearly from 25°C	2.0	mW/°C				

Electrical Characteristics ($T_A = 25^{\circ}C$ unless otherwise specified)

Individual Component Characteristics

Symbol	Parameters	Parameters Test Conditions De		Min.	Тур.*	Max.	Units
EMITTER				1			
V _F	Input Forward Voltage	I _F = 5mA	All		1.25	1.5	V
$\frac{\Delta V_{F}}{\Delta T_{A}}$	Forward Voltage Temp. Coefficient	I _F = 2mA	All		-1.75		mV/°C
V _R	Reverse Voltage	Ι _R = 10μΑ	All	6			V
CJ	Junction Capacitance	V _F = 0V, f = 1.0MHz	All		18		pF
DETECTO	R						
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 1.0mA, I _F = 0	All	30	100		V
BV _{CBO}	Collector-Base Breakdown Voltage	Ι _C = 10μΑ, Ι _F = 0	All	30	120		V
BV _{EBO}	Emitter-Base Breakdown Voltage	Ι _E = 10μΑ, Ι _F = 0	All	5	10		V
I _{CER}	Collector-Emitter Dark Current	$V_{CE} = 10V, I_F = 0,$ $R_{BE} = 1M\Omega$	All		1	100	nA
C _{CE}	Capacitance, Collector to Emitter	V _{CE} = 0, f = 1MHz	All		10		pF
C _{CB}	Capacitance, Collector to Base	V _{CB} = 0, f = 1MHz	All		80		pF
C _{EB}	Capacitance, Emitter to Base	V _{EB} = 0, f = 1MHz	All		15		pF

Isolation Characteristics

Symbol	Characteristic	Test Conditions	Device	Min.	Тур.*	Max.	Units
V _{ISO}	Input-Output Isolation Voltage ⁽¹⁰⁾	f = 60Hz, t = 1 sec.	All	7500			Vac(peak)
R _{ISO}	Isolation Resistance ⁽¹⁰⁾	V _{I-O} = 500 VDC, T _A = 25°C	All	10 ¹¹			Ω
C _{ISO}	Isolation Capacitance ⁽⁹⁾	V _{I-O} = 0, f = 1 MHz	All		0.4	0.6	pF
CM _H	Common Mode Transient	$V_{CM} = 50 V_{P-P1}, R_L = 750\Omega, I_F = 0$	MCT5210M/11M		5000		V/µs
	Rejection – Output HIGH	$V_{CM} = 50 V_{P-P}, R_L = 1K\Omega,$ $I_F = 0$	MCT5201M				
CML	Common Mode Transient	$V_{CM} = 50 V_{P-P1}, R_L = 750\Omega,$ $I_F = 1.6 mA$	MCT5210M/11M		5000		V/µs
	Rejection – Output LOW	V_{CM} = 50 V_{P-P1} , R_L = 1K Ω , I_F = 5mA	MCT5201M				

*All typical $T_A = 25^{\circ}C$

Electrical Characteristics (Continued) ($T_A = 25^{\circ}C$ unless otherwise specified)

Transfer Characteristics

Symbol	Characteristics	Test Conditions		Device	Min.	Тур.*	Max.	Units
DC CHARA	CTERISTICS			•				
CTR _{CE(SAT)}	Saturated Current	I _F = 5mA, V _{CE} = 0.4V		MCT5201M	120			%
	Transfer Ratio ⁽¹⁾	I _F = 3.0mA, V _{CE} = 0.4V		MCT5210M	60			
	(Collector to Emitter)	I _F = 1.6mA, V _{CE} = 0.4V		MCT5211M	100			ĺ
		I _F = 1.0mA, V _{CE} = 0.4V		-	75			
CTR _(CE)	Current Transfer Ratio	I _F = 3.0mA, V _{CE} = 5.0V		MCT5210M	70			%
()	(Collector to Emitter) ⁽¹⁾	I _F = 1.6mA, V _{CE} = 5.0V		MCT5211M	150			
		I _F = 1.0mA, V _{CE} = 5.0V		-	110			
CTR _(CB)	Current Transfer Ratio	I _F = 5mA, V _{CB} = 4.3V		MCT5201M	0.28			%
()	Collector to Base ⁽²⁾	I _F = 3.0mA, V _{CE} = 4.3V		MCT5210M	0.2			
		I _F = 1.6mA, V _{CE} = 4.3V		MCT5211M	0.3			
		I _F = 1.0mA, V _{CE} = 4.3V		-	0.25			
V _{CE(SAT)}	Saturation Voltage	$I_{\rm F} = 5 {\rm mA}, I_{\rm CF} = 6 {\rm mA}$		MCT5201M			0.4	V
0 = (0,)		I _F = 3.0mA, I _{CE} = 1.8mA		MCT5210M			0.4	-
		I _F = 1.6mA, I _{CE} = 1.6mA		MCT5211M			0.4	
AC CHARA	CTERISTICS							
T _{PHL}	Propagation Delay HIGH-to-LOW ⁽³⁾	R _I = 330 Ω, R _{BE} = ∞	I _F = 3.0mA,	MCT5210M		10		μs
1112		$R_L = 3.3 k\Omega$, $R_{BE} = 39kΩ$	V _{CC} = 5.0V			7		
		R _L = 750 Ω, R _{BE} = ∞	I _F = 1.6mA,	.0V nA,		14		
		$R_L = 4.7 k\Omega$, $R_{BE} = 91 k\Omega$	V _{CC} = 5.0V			15		
		R _L = 1.5 kΩ, R _{BE} = ∞	I _F = 1.0mA,			17		
		$R_{\rm L}$ = 10 kΩ, $R_{\rm BE}$ = 160kΩ	V _{CC} = 5.0V			24		
		$V_{CE} = 0.4V, V_{CC} = 5V,$ R _L = fig. 13, R _{BE} = 330k Ω	I _F = 5mA	MCT5201M		3	30	
T _{PLH}	Propagation Delay LOW-to-HIGH ⁽⁴⁾	R _L = 330 Ω, R _{BE} = ∞	I _F = 3.0mA,	MCT5210M		0.4		μs
		$R_L = 3.3 \text{ k}\Omega, R_{BE} = 39 \text{k}\Omega$	V _{CC} = 5.0V			8		
		R _L = 750 Ω, R _{BE} = ∞	I _F = 1.6mA,	MCT5211M		2.5		
		R _L = 4.7 kΩ, R _{BE} = 91kΩ	V _{CC} = 5.0V			11		-
		R _L = 1.5 kΩ, R _{BE} = ∞	I _F = 1.0mA,			7	1	
		R _L = 10 kΩ, R _{BE} = 160kΩ	V _{CC} = 5.0V			16	7	
		$V_{CE} = 0.4V, V_{CC} = 5V,$ R _L = fig. 13, R _{BE} = 330k Ω	I _F = 5mA	MCT5201M		12	13	
t _d	Delay Time ⁽⁵⁾	$V_{CE} = 0.4V, R_{BE} = 330k\Omega,$ $R_{L} = 1 k\Omega, V_{CC} = 5V$	I _F = 5mA	MCT5201M		1.1	15	μs
t _r	Rise Time ⁽⁶⁾	$V_{CE} = 0.4V, R_{BE} = 330k\Omega,$ $R_{L} = 1 k\Omega, V_{CC} = 5V$	I _F = 5mA	MCT5201M		2.5	20	μs
t _s	Storage Time ⁽⁷⁾	$V_{CE} = 0.4V, R_{BE} = 330 \text{ k}\Omega,$ $R_{L} = 1 \text{ k}\Omega, V_{CC} = 5V$	I _F = 5mA	MCT5201M		10	13	μs
t _f	Fall Time ⁽⁸⁾	$V_{CE} = 0.4V, R_{BE} = 330 \text{ k}\Omega,$ $R_{L} = 1 \text{ k}\Omega, V_{CC} = 5V$	I _F = 5mA	MCT5201M		16	30	μs

*All typicals at $T_A = 25^{\circ}C$

MCT5201M, MCT5210M, MCT5211M — Low Input Current Phototransistor Optocouplers

Notes:

- 1. DC Current Transfer Ratio (CTR_{CE}) is defined as the transistor collector current (I_{CE}) divided by the input LED current (I_F) x 100%, at a specified voltage between the collector and emitter (V_{CE}).
- The collector base Current Transfer Ratio (CTR_{CB}) is defined as the transistor collector base photocurrent(I_{CB}) divided by the input LED current (I_F) time 100%.
- Referring to Figure 14 the T_{PHL} propagation delay is measured from the 50% point of the rising edge of the data input pulse to the 1.3V point on the falling edge of the output pulse.
- Referring to Figure 14 the T_{PLH} propagation delay is measured from the 50% point of the falling edge of data input pulse to the 1.3V point on the rising edge of the output pulse.
- 5. Delay time (t_d) is measured from 50% of rising edge of LED current to 90% of Vo falling edge.
- 6. Rise time (t_r) is measured from 90% to 10% of Vo falling edge.
- 7. Storage time (t_s) is measured from 50% of falling edge of LED current to 10% of Vo rising edge.
- 8. Fall time (t_f) is measured from 10% to 90% of Vo rising edge.
- 9. CISO is the capacitance between the input (pins 1, 2, 3 connected) and the output, (pin 4, 5, 6 connected).
- 10. Device considered a two terminal device: Pins 1, 2, and 3 shorted together, and pins 5, 6 and 7 are shorted together.

Safety and Insulation Ratings

As per IEC 60747-5-2, this optocoupler is suitable for "safe electrical insulation" only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

Symbol	Parameter	Min.	Тур.	Max.	Unit
	Installation Classifications per DIN VDE 0110/1.89 Table 1				
	For Rated Main Voltage < 150Vrms		I-IV		
	For Rated Main voltage < 300Vrms		I-IV		
	Climatic Classification		55/100/21		
	Pollution Degree (DIN VDE 0110/1.89)		2		
CTI	Comparative Tracking Index	175			
V _{PR}	Input to Output Test Voltage, Method b, $V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test with tm = 1 sec, Partial Discharge < 5pC	1594			V _{peak}
	Input to Output Test Voltage, Method a, $V_{IORM} \times 1.5 = V_{PR}$, Type and Sample Test with tm = 60 sec, Partial Discharge < 5pC	1275			V _{peak}
V _{IORM}	Max. Working Insulation Voltage	850			V _{peak}
V _{IOTM}	Highest Allowable Over Voltage	6000			V _{peak}
	External Creepage	7			mm
	External Clearance	7			mm
	Insulation Thickness	0.5			mm
RIO	Insulation Resistance at Ts, V_{IO} = 500V	10 ⁹	1		Ω



Fig. 3 Normalized CTR vs. Temperature NORMALIZED CURRENT TRANSFER RATIO 1.4 10 NORMALIZED ICE – COLLECTOR-EMITTER CURRENT Normalized to: $I_F = 5mA$ 1.2 $V_{CE} = 5V$ $I_F = 10 mA$ $I_F = 5mA$ T_A = 25°C 1.0 0.1 0.8 $l_{\rm E} = 2m/$ 0.6 0.01 $I_F = 1mA$ 0.4 $I_F = 0.5 m A$ 0.001 0.2 $I_F = 0.2 m A$ 0.0001 L 0.1 0.0 40 -20 -20 0 20 40 60 100 120 TA – AMBIENT TEMPERATURE (°C) Fig. 5 Normalized Collector Base Photocurrent **Ratio vs. Forward Current** NORMALIZED I_{CB} – COLLECTOR-BASE PHOTO CURRENT 100 10 NORMALIZED COLLECTOR-BASE CURRENT 10 1 0.1 1 Normalized to: 0.01 0.1 = 5mA $V_{CB} = 4.3V$ $T_A = 25^{\circ}C$ 0.01 0.001 10 100

Typical Performance Curves

2.0

1.8

1.6

1.4

1.2

1.0

0.8

0.1

 $T_A = -40^{\circ}C$

T_A = 25°C

VF – FORWARD VOLTAGE (V)

Fig. 1 LED Forward Voltage vs. Forward Current

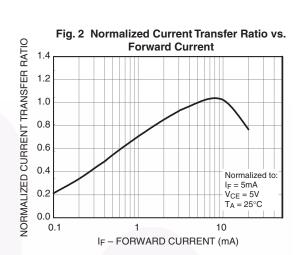
T_A = 100°C

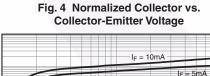
IF - LED FORWARD CURRENT (mA)

1

10

100





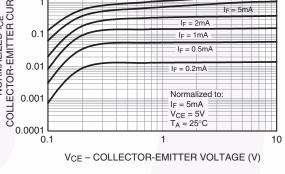
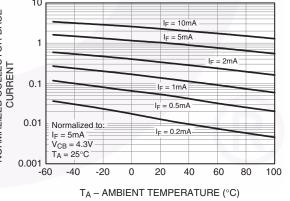


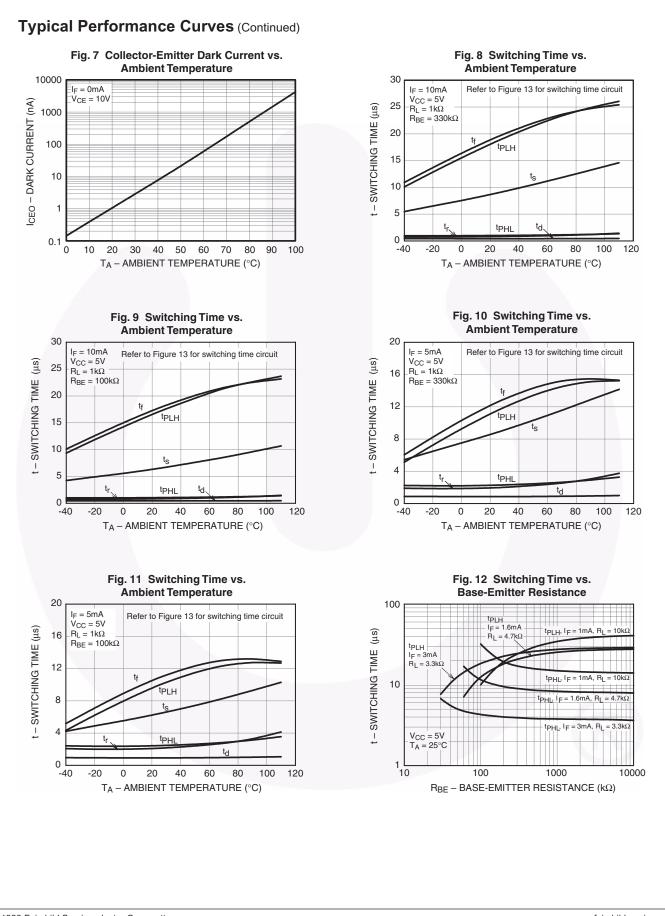
Fig. 6 Normalized Collector-Base Current vs. Temperature

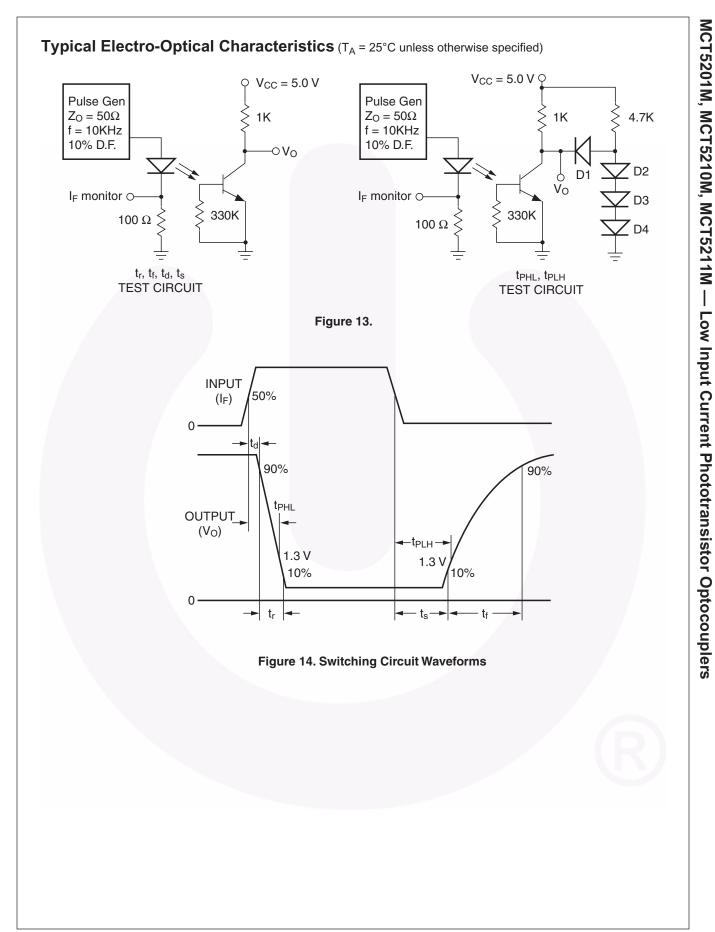


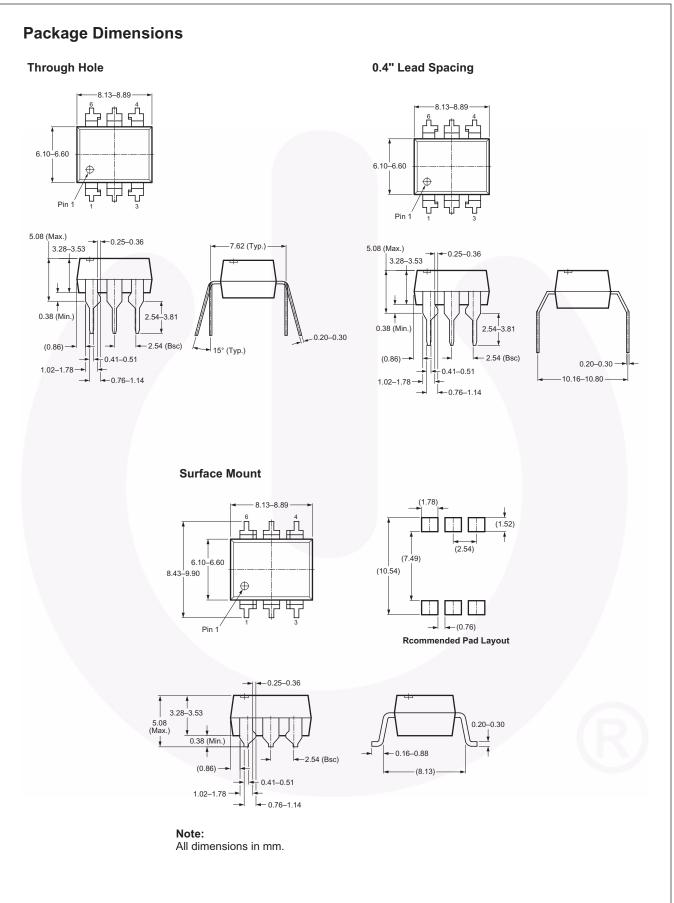
1

IF - FORWARD CURRENT (mA)

0.1





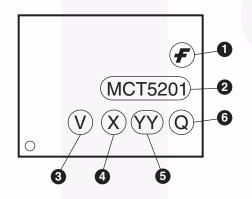


Ordering Information Order Entry Identifier Option (Example) Description MCT5201M Standard Through Hole Device (50 units per tube) No suffix S MCT5201SM Surface Mount Lead Bend SR2 Surface Mount; Tape and Reel (1,000 units per reel) MCT5201SR2M Т MCT5201TM 0.4" Lead Spacing V MCT5201VM IEC60747-5-2 ΤV MCT5201TVM IEC60747-5-2, 0.4" Lead Spacing SV MCT5201SVM IEC60747-5-2, Surface Mount

Marking Information

MCT5201SR2VM

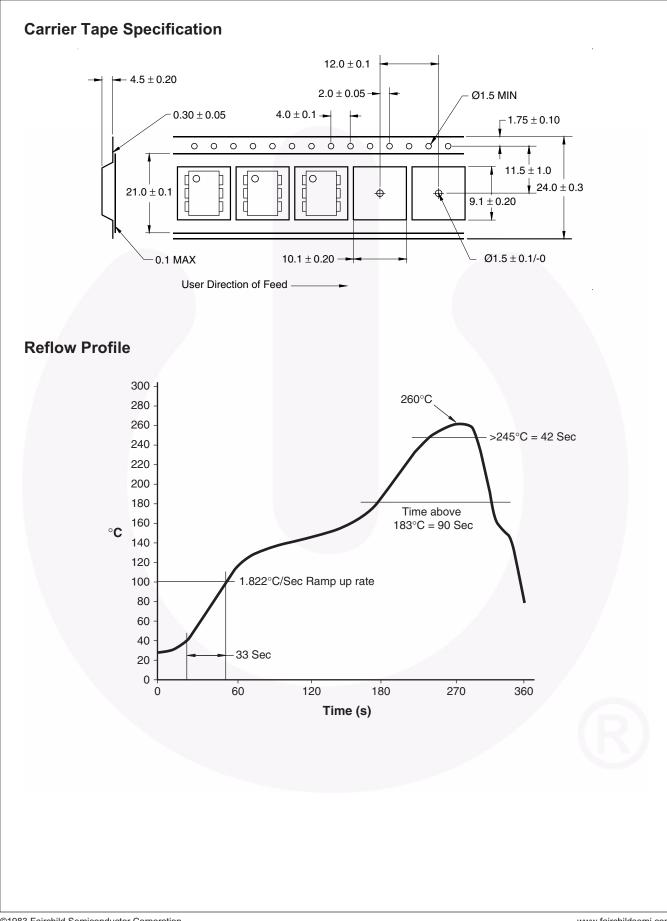
SR2V

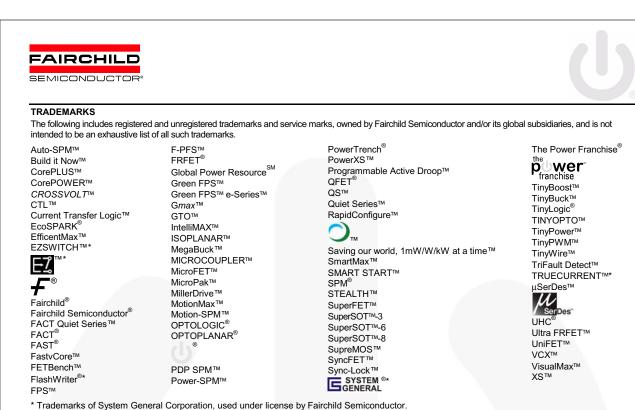


IEC60747-5-2, Surface Mount, Tape and Reel (1,000 units per reel)

Definitions					
1	Fairchild logo				
2	Device number				
3	VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table)				
4	One digit year code, e.g., '7'				
5	Two digit work week ranging from '01' to '53'				
6	Assembly package code				

*Note – Parts that do not have the 'V' option (see definition 3 above) that are marked with date code '325' or earlier are marked in portrait format.





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PRODUCT STATUS DEFINITIONS

Definition of Terms						
Datasheet Identification	Product Status	Definition				
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.				
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.				
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.				
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.				